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PAPERS

**Liquid Crystal Displays**

- Polymer Network Liquid Crystal (PNLC) Lenticular Microlens Array With No Surface Treatment ..... *X. Wang, H. Ren, and Q. Wang* 773
- Bistable Light Shutter Using Dye-doped Cholesteric Liquid Crystals Driven with Crossed Patterned Electrodes ..... *J.-W. Huh, S.-M. Ji, J. Heo, B.-H. Yu, and T.-H. Yoon* 779

**OLED Displays**

- Adaptive Color Saturation Control for Low Power RGBW OLED Displays ..... *J.-H. Choi, M. Lee, K. Kang, and J.-O. Kim* 784
- Perceptually Hue-Oriented Power-Saving Scheme with Overexposure Corrector for AMOLED Displays ..... *P. Chondro and S.-J. Ruan* 791
- Outcoupling Efficiency Analysis of OLEDs Fabricated on a Wrinkled Substrate ..... *J.-H. Park, W.-S. Chu, M.-C. Oh, K. Lee, J. Moon, S. K. Park, H. Cho, and D.-H. Cho* 801
- Analysis of the Dependence of the Viewing Zones on the Display Radius in Autostereoscopic 2 View Displays of Horizontally Concave Surface ..... *H. K. Hong* 808

**3-D Displays**

- Fast Hologram Pattern Generation by Adaptive Point-Spread Spherical Wave Synthesis ..... *Y. Mori and T. Nomura* 815
- Fabrication of Micro-lens Arrays Based on Ink-jet Printing and Photolithographic Hole Templates for Integral Imaging 3-D Display ..... *Y. Peng, R. Peng, Z. Chu, X. Zhou, Y. Zhang, and T. Guo* 822

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(Contents Continued on Page 772)

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**Backplanes**

An Area-Efficient High-Resolution Resistor-String DAC with Reverse Ordering Scheme for Active Matrix Flat-Panel Display Data Driver ICs ..... *H.-C. Seol, S.-K. Hong, and O.-K. Kwon* 828

Dual-Gate Photosensitive a-Si:H TFT Array Enabling Fingerprint-Sensor-Integrated Display Application ..... *M. Xu, H. Li, H. Ou, J. Chen, S. Deng, N. Xu, and K. Wang* 835

**Visual Perception**

On the Influence of Distance in the Interaction With Large Displays ..... *A. X. Li, X. Lou, P. Hansen, and R. Peng* 840

Simulation of Blur in Transmitted Image through Transparent Plastic for Transparent OLEDs ..... *H.-J. Kwon, C.-M. Yang, M.-C. Kim, C.-W. Kim, J.-Y. Ahn, and P.-R. Kim* 851

**Head-Up Displays**

A Novel Experimental Approach for Thermal Stress Measurement in Elastomerically Mounted Optics of Head-Up Display System ..... *V. A. S. K. RR, H. Garg, and V. Karar* 859

**Light-Emitting Diodes**

Improving the Brightness and Reliability of InGaN/GaN Near Ultraviolet Light-Emitting Diodes by Controlling the Morphology of the GaN Buffer Layer ..... *S.-C. Tsai, H.-C. Fang, C.-H. Lu, Y.-L. Lai, and C.-P. Liu* 869

Red-Phosphor-Dot-Doped Array in Mirror-Surface Substrate Light-Emitting Diodes ..... *H. Xiao, Y. Lu, C. Chai, Y. Wang, T. Shih, and Z. Chen* 873

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